

**Search Notes**

Application/Control No.

09/964,910

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

YAMAURA ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	12	1/3/2006	DWY
429	40	1/3/2006	DWY
429	44	1/3/2006	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
429	12	1/3/2006	DWY
429	40	1/3/2006	DWY
429	44	1/3/2006	DWY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/3/2006	DWY
Inventorship Search	1/3/2006	DWY